

Growth of Individual Carbon Nanotubes with Precise location

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Abstract

Electronic devices based on individual single-walled carbon nanotubes (SWCNTs) remain at the prototype level because of the limited reliability of the growth processes and the absence of control over electrical properties and positioning of the obtained nanotubes. To improve the location and narrow the electronic property distribution of the SWCNTs, we have developed a method based on a negative-tone e-beam resist doped with Co. At the end of the process, individual particles with a diameter of 1.2±0.2nm are localized within an area of 80nm². From these

particles, high-quality SWCNTs are grown by a Chemical Vapor Deposition (CVD) with high yield from ethanol. The process is being integrated into the fabrication process of the nano electro-mechanical system (NEMS) developed by our partners at ETHZ.

Catalyst formation process



Characterization of the Catalyst Particles



Growth of Single-walled carbon nanotubes



- **Growth temperature: 800°C**
 - **Carbon source: Ethanol AFM** analysis **CNT** diameter (nm) d_{av.}=1.2nm **σ=0.25nm**

HIGHLIGHTS:

- Localisation of one particle within an area of 80nm²
- **Narrow Particle Diameter Distribution**

according to the RIE time and the Co concentration in the calix[6]arene resist.

Colored high resolution SEM micrograph and its schematic representation. A SWCNT is grown by CVD from ethanol over a 2µm deep trench from one patterned Co nanoparticles. It has a diameter of 1.2±0.25nm corresponding to the diameter of the Co nanoparticles.



100% of the particles yield a SWCNT



SEM micrograph of a NEMS with patterned catalyst particle.

1 Cobalt nanoparticle (NP) in a 250nm² area established by AFM analysis, for different Co concentrations in the calix[6]arene resist.

Raman spectra of the grown SWCNTs for three concentrations of Co in the resist. Nanotube structure contains limited defects. Despite the increase of the metal concentration, their average diameter remains in the 1.2nm range.

For a defined patterned area, the increase of the Co concentration in the resist leads to the growth of bundles of 1.2nm SWCNTs.

Acknowledgements

This research has been funded by Nano-Tera.ch, a program of the Swiss Confederation, evaluated by SNSF.

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